Richard Arinero

List of Publications by Year
in descending order

37 papers	561 citations	623734 14 h-index	642732 23 g-index
37 all docs	37 docs citations	37 times ranked	553 citing authors

#	Article	IF	Citations
1	Determination of the nanoscale dielectric constant by means of a double pass method using electrostatic force microscopy. Journal of Applied Physics, 2009, 106, .	2.5	73
2	Nanodielectric mapping of a model polystyrene-poly(vinyl acetate) blend by electrostatic force microscopy. Physical Review E, 2010, 81, 010801.	2.1	53
3	Imaging dielectric relaxation in nanostructured polymers by frequency modulation electrostatic force microscopy. Applied Physics Letters, 2010, 96, 213110.	3.3	47
4	Vibration of the cantilever in Force Modulation Microscopy analysis by a finite element model. Review of Scientific Instruments, 2003, 74, 104-111.	1.3	41
5	Towards a better understanding of wood cell wall characterisation with contact resonance atomic force microscopy. Composites Part A: Applied Science and Manufacturing, 2015, 74, 69-76.	7.6	32
6	Imaging the Mechanical Properties of Wood Cell Wall Layers by Atomic Force Modulation Microscopy. IAWA Journal, 2003, 24, 223-230.	2.7	28
7	Broadband nanodielectric spectroscopy by means of amplitude modulation electrostatic force microscopy (AM-EFM). Ultramicroscopy, 2011, 111, 1366-1369.	1.9	25
8	Force gradient detection under vacuum on the basis of a double pass method. Review of Scientific Instruments, 2006, 77, 096101.	1.3	24
9	Nanoscale surface charge detection in epoxy resin materials using electrostatic force spectroscopy. AIP Advances, 2016, 6, .	1.3	24
10	Characterization of Dielectric Nanocomposites with Electrostatic Force Microscopy. Scanning, 2017, 2017, 1-14.	1.5	21
11	Nanoscale dielectric properties of insulating thin films: From single point measurements to quantitative images. Ultramicroscopy, 2010, 110, 634-638.	1.9	20
12	Development of ruthenium dioxide electrodes for pyroelectric devices based on lithium tantalate thin films. Thin Solid Films, 2007, 515, 3971-3977.	1.8	18
13	Numerical simulations of electrostatic interactions between an atomic force microscopy tip and a dielectric sample in presence of buried nano-particles. Journal of Applied Physics, 2012, 112, .	2.5	15
14	Near field imaging of a semiconductor laser by scanning probe microscopy without a photodetector. Applied Physics Letters, 2013, 103, 053120.	3.3	14
15	New method for electrostatic force gradient microscopy observations and Kelvin measurements under vacuum. Ultramicroscopy, 2007, 107, 1027-1032.	1.9	12
16	Capacitive silicon micro-electromechanical resonator for enhanced photoacoustic spectroscopy. Applied Physics Letters, 2019, 115, .	3.3	12
17	High fluence 1.8MeV proton irradiation effects on n-type MOS capacitors. Microelectronics Reliability, 2011, 51, 2093-2096.	1.7	11
18	Electrostatic force microscopy for the accurate characterization of interphases in nanocomposites. Beilstein Journal of Nanotechnology, 2018, 9, 2999-3012.	2.8	11

#	Article	IF	Citations
19	Contrast inversion in electrostatic force microscopy imaging of trapped charges: tipâ€“sample distance and dielectric constant dependence. Nanotechnology, 2011, 22, 345702.	2.6	10
20	High-Energy Heavy Ion Irradiation-Induced Structural Modifications: A Potential Physical Understanding of Latent Defects. IEEE Transactions on Nuclear Science, 2008, 55, 2970-2974.	2.0	9
21	Investigation of EFM capabilities for probing interphases in nanodielectric materials: A numerical study. , 2016, , .		9
22	Apertureless scanning microscope probe as a detector of semiconductor laser emission. Applied Physics Letters, 2015, 106, 171105.	3.3	7
23	Post-Irradiation-Gate-Stress on Power MOSFETs: Quantification of Latent Defects-Induced Reliability Degradation. IEEE Transactions on Nuclear Science, 2013, 60, 4166-4174.	2.0	6
24	Compatibility studies of polystyrene and poly(vinyl acetate) blends using electrostatic force microscopy. Journal of Polymer Science, Part B: Polymer Physics, 2011, 49, 1332-1338.	2.1	5
25	Impact of Single Event Gate Rupture and Latent Defects on Power MOSFETs Switching Operation. IEEE Transactions on Nuclear Science, 2014, 61, 1856-1864.	2.0	5
26	Magnetic flux distortion in two-phase liquid metal flow: Model experiment. Journal of Applied Physics, 2016, 119, .	2.5	5
27	Pedestal formation of all-semiconductor gratings through GaSb oxidation for mid-IR plasmonics. Journal Physics D: Applied Physics, 2018, 51, 015104.	2.8	5
28	Half-disk laser: insight into the internal mode structure of laser resonators. Optics Express, 2018, 26, 14433.	3.4	5
29	PbTiO3 thin films grown by mixed reactive thermal co-evaporation. Journal of Crystal Growth, 2007, 304, 383-387.	1.5	4
30	Influence of the surrounding ambient on the reliability of the electrical characterization of thin oxide layers using an atomic force microscope. Microelectronics Reliability, 2011, 51, 2097-2101.	1.7	4
31	Mid-IR plasmonic compound with gallium oxide toplayer formed by GaSb oxidation in water. Semiconductor Science and Technology, 2018, 33, 095009.	2.0	3
32	STRUCTURAL PROPERTIES OF PbTiO₃ FILMS GROWN BY MIXED REACTIVE THERMAL CO-EVAPORATION. Integrated Ferroelectrics, 2008, 98, 161-170.	0.7	1
33	Temperature and damping effects on the frequency dependence of electrostatic force microscopy force gradients. Journal of Applied Physics, 2013, 114, 214315.	2.5	1
34	High-resolution electrical characterization of RuO2-borosilicate glass composites. Journal of Alloys and Compounds, 2021, 876, 160123.	5.5	1
35	Conductive atomic force microscopy as a tool to reveal high ionising dose effects on ultra thin SiO2/Si structures. Applied Nanoscience (Switzerland), 2013, 3, 235-240.	3.1	0
36	Stable and Unstable Spatial Modes in a Resonator with a Half-Disk Shape. Semiconductors, 2018, 52, 2046-2048.	0.5	0

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37	New Insights into Dielectric Nanocomposites by EFM Imaging and Spectroscopy. , 2018, , .		0